

# Guo Chenjun

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9136643/publications.pdf>

Version: 2024-02-01

10  
papers

111  
citations

1307594

7  
h-index

1474206

9  
g-index

10  
all docs

10  
docs citations

10  
times ranked

90  
citing authors

#	ARTICLE	IF	CITATIONS
1	A Semisupervised Learning Framework for Recognition and Classification of Defects in Transient Thermography Detection. IEEE Transactions on Industrial Informatics, 2022, 18, 2632-2640.	11.3	9
2	Photothermal Radar Shearography: A Novel Transient-Based Speckle Pattern Interferometry for Depth-Tomographic Inspection. IEEE Transactions on Industrial Informatics, 2022, 18, 4352-4360.	11.3	4
3	Health Monitoring of RTV Silicone Rubber Coating on Insulators Based on Multimode Features of Active Infrared Thermography. IEEE Transactions on Instrumentation and Measurement, 2022, 71, 1-9.	4.7	1
4	Transient thermal pattern separation and detection of conductive defects in composite insulators using eddy current pulsed thermography. NDT and E International, 2022, 129, 102653.	3.7	9
5	Pixel-Level Classification of Pollution Severity on Insulators Using Photothermal Radiometry and Multiclass Semisupervised Support Vector Machine. IEEE Transactions on Industrial Informatics, 2021, 17, 441-449.	11.3	25
6	Differential Evolution Fitting-Based Optical Step-Phase Thermography for Micrometer Thickness Measurement of Atmospheric Corrosion Layer. IEEE Transactions on Industrial Informatics, 2020, 16, 5213-5222.	11.3	15
7	Eddy Current Thermography for the Detection of Conductive Defects in Composite Insulators. , 2020, , .		0
8	Remote Optical Thermography Detection Method and System for Silicone Polymer Insulating Materials Used in Power Industry. IEEE Transactions on Instrumentation and Measurement, 2020, 69, 5782-5790.	4.7	15
9	Detecting Defects in Porcelain Postinsulator Coated With Room Temperature Vulcanized Silicone Rubber by Pulsed Thermography. IEEE Transactions on Instrumentation and Measurement, 2019, 68, 225-233.	4.7	19
10	Nondestructive Visualization and Quantitative Characterization of Defects in Silicone Polymer Insulators Based on Laser Shearography. IEEE Sensors Journal, 2019, 19, 6508-6516.	4.7	14